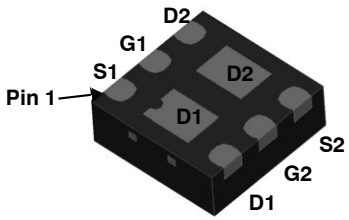
MOSFET – Dual, N-Channel, POWERTRENCH®

20 V, 3.8 A, 66 mΩ

FDME1024NZT



MicroFET
UDFN6 1.6X1.6, 0.5P
CASE 517DW

Description

This Device is Designed Specifically as a Single Package Solution for Dual Switching Requirement in cellular handset and other Ultra−Portable Applications. It features two independent N−Channel MOSFETs with low on−state resistance for minimum conduction losses.

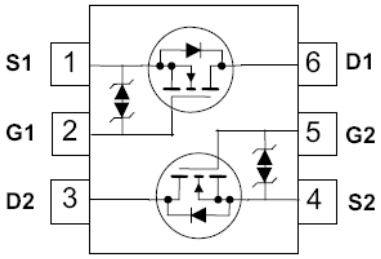
The MicroFET™ 1.6x1.6 Thin package offers Exceptional Thermal Performance for it's physical size and is well suited to switching and linear mode applications.

Features

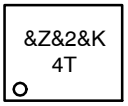
- Max $R_{DS(on)}$ = 66 mΩ at V_{GS} = 4.5 V, I_D = 3.4 A
- Max $R_{DS(on)}$ = 86 mΩ at V_{GS} = 2.5 V, I_D = 2.9 A
- Max $R_{DS(on)}$ = 113 mΩ at V_{GS} = 1.8 V, I_D = 2.5 A
- Max $R_{DS(on)}$ = 160 mΩ at V_{GS} = 1.5 V, I_D = 2.1 A
- Low Profile 0.55 mm Maximum – in the New Package MicroFET 1.6x1.6 Thin
- Free From Halogenated Compounds and Antimony Oxides
- HBM ESD Protection Level > 1600 V (Note 3)
- These Devices is Pb−Free, Halide Free and is RoHS Compliant

Typical Applications

- Baseband Switch
- Load Switch



MARKING DIAGRAM



&Z = Assembly Plant Code
&2 = 2−Digit Date−Code (Year & Week)
&K = 2−Digit Lot Traceability Code
4T = Specific Device Code

ABSOLUTE MAXIMUM RATINGS T_A = 25°C unless otherwise noted

Symbol	Parameter	Value	Unit
V_{DS}	Drain to Source Voltage	20	V
V_{GS}	Gate to Source Voltage	±8	V
I_D	Drain Current T_A = 25°C − Continuous (Note 1a) − Pulsed	 3.8 6	A
P_D	Power Dissipation Single Operation T_A = 25°C (Note 1a)	1.4	W
	Power Dissipation Single Operation T_A = 25°C (Note 1b)	0.6	
T_J, T_{stg}	Operating and Storage Junction Temperature Range	−55 to +150	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

ORDERING INFORMATION

Device	Package	Shipping†
FDME1024NZT	UDFN−6 (Pb−Free)	5000 / Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

THERMAL CHARACTERISTICS

Symbol	Parameter	Value	Unit
$R_{\theta JA}$	Thermal Resistance for, Junction to Ambient (Single Operation) (Note 1a)	90	°C/W
$R_{\theta JA}$	Thermal Resistance for, Junction to Ambient (Single Operation) (Note 1b)	195	°C/W

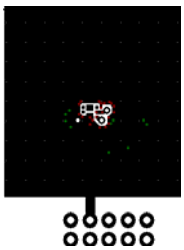
ELECTRICAL CHARACTERISTICS T_J = 25°C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Typ	Max	Unit
Off Characteristics						
BV_{DSS}	Drain to Source Breakdown Voltage	I_D = 250 μA, V_{GS} = 0 V	20	–	–	V
$\frac{\Delta BV_{DSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	I_D = 250 μA, Referenced to 25°C	–	16	–	mV/°C
I_{DSS}	Zero Gate Voltage Drain Current	V_{DS} = 16 V, V_{GS} = 0 V	–	–	1	μA
I_{GSS}	Gate to Source Leakage Current	V_{GS} = ±8 V, V_{DS} = 0 V	–	–	±10	μA
On Characteristics						
$V_{GS(th)}$	Gate to Source Threshold Voltage	V_{GS} = V_{DS}, I_D = 250 μA	0.4	0.7	1.0	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	I_D = 250 μA, Referenced to 25°C	–	–3	–	mV/°C
$R_{DS(on)}$	Static Drain–Source On–Resistance	V_{GS} = 4.5 V, I_D = 3.4 A V_{GS} = 2.5 V, I_D = 2.9 A, V_{GS} = 1.8 V, I_D = 2.5 A, V_{GS} = 1.5 V, I_D = 2.1 A, V_{GS} = 4.5 V, I_D = 3.4 A, T_J = 125°C	– – – – –	55 68 85 106 76	66 86 113 160 112	mΩ
g_{FS}	Forward Transconductance	V_{DS} = 4.5 V, I_D = 3.4 A	–	9	–	S
Dynamic Characteristics						
C_{iss}	Input Capacitance	V_{DS} = 10 V, V_{GS} = 0 V, f = 1 MHz	–	225	300	pF
C_{oss}	Output Capacitance		–	40	55	pF
C_{rss}	Reverse Transfer Capacitance		–	25	40	pF
Switching Characteristics						
$t_{d(on)}$	Turn–On Delay Time	V_{DD} = 10 V, I_D = 1 A, V_{GS} = 4.5 V, R_{GEN} = 6 Ω	–	4.5	10	ns
t_r	Rise Time		–	2	10	ns
$t_{d(off)}$	Turn–Off Delay Time		–	15	27	ns
t_f	Fall Time		–	1.7	10	ns
Q_g	Total Gate Charge	V_{DD} = 10 V, I_D = 3.4 A, V_{GS} = 4.5 V	–	3	4.2	nC
Q_{gs}	Gate to Source Gate Charge		–	0.4	–	nC
Q_{gd}	Gate to Drain “Miller” Charge		–	0.6	–	nC
Drain–Source Diode Characteristics and Maximum Ratings						
V_{SD}	Source to Drain Diode Forward Voltage	V_{GS} = 0 V, I_S = 0.9 A (Note 2)	–	0.7	1.2	V
t_{rr}	Reverse Recovery Time	I_F = 3.4 A, di/dt = 100 A/μs	–	8.5	17	ns
Q_{rr}	Reverse Recovery Charge		–	1.4	10	nC

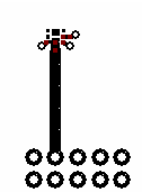
Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

NOTES:

1. $R_{\theta JA}$ is determined with the device mounted on a 1 in^2 oz. copper pad on a 1.5 x 1.5 in. board of FR−4 material. $R_{\theta JC}$ is guaranteed by design while $R_{\theta CA}$ is determined by the user's board design.



a).90 °C/W when mounted on a 1 in^2 pad of 2 oz copper.



b).195 °C/W when mounted on a minimum pad of 2 oz copper.

2. Pulse Test: Pulse Width ≤ 300 μs, Duty Cycle ≤ 2.0%
3. The diode connected between the gate and source serves only as protection against ESD. No gate overvoltage rating is implied.

TYPICAL CHARACTERISTICS T_C = 25°C unless otherwise noted

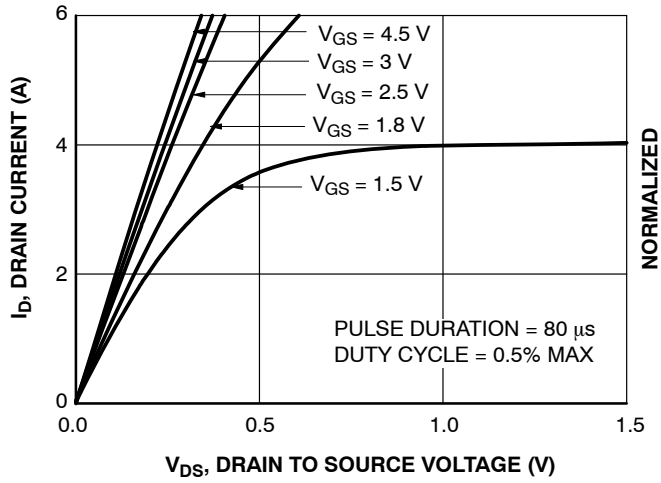


Figure 1. On−Region Characteristics

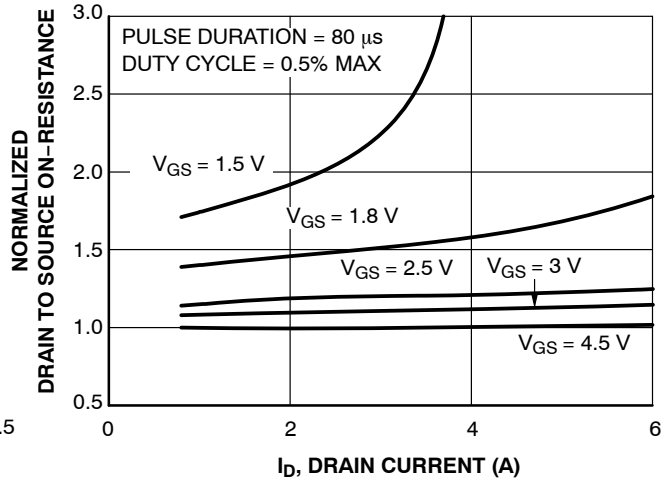


Figure 2. Normalized On−Resistance vs. Drain Current and Gate Voltage

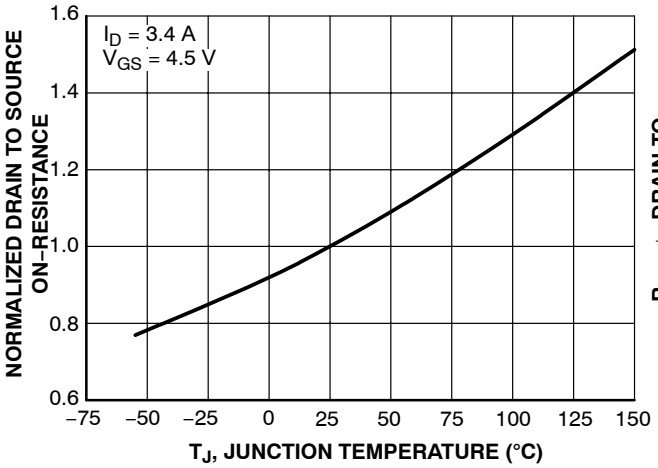


Figure 3. Normalized On−Resistance vs Junction Temperature

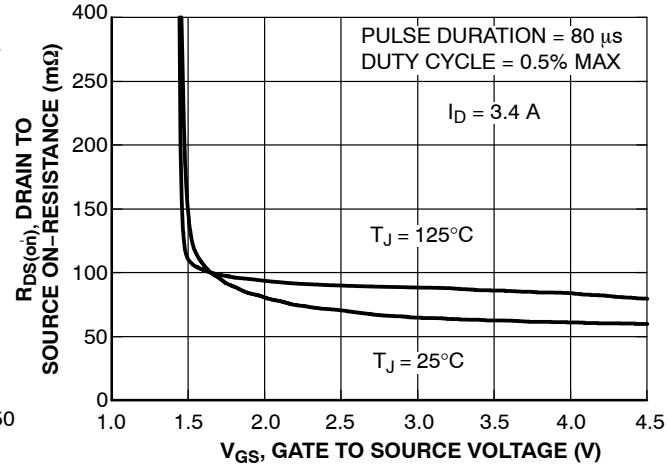


Figure 4. On−Resistance vs Gate to Source Voltage

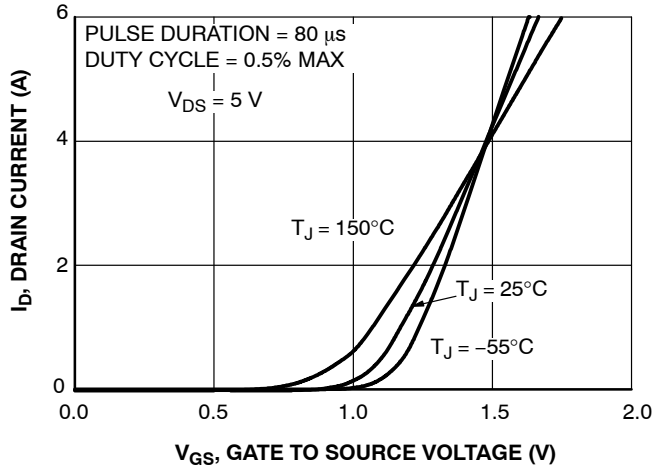


Figure 5. Transfer Characteristics

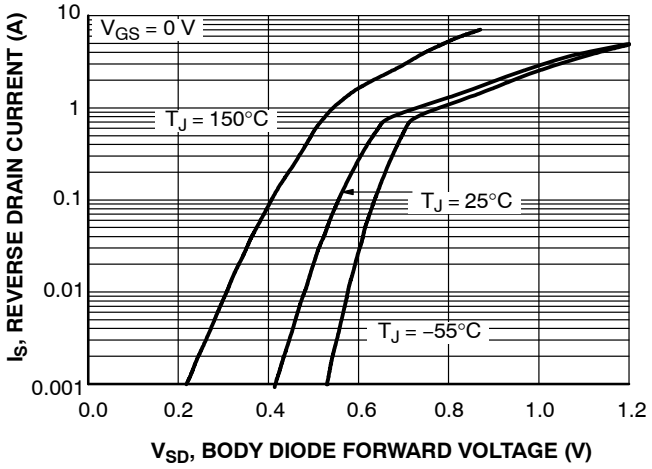


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

TYPICAL CHARACTERISTICS T_C = 25°C unless otherwise noted (CONTINUED)

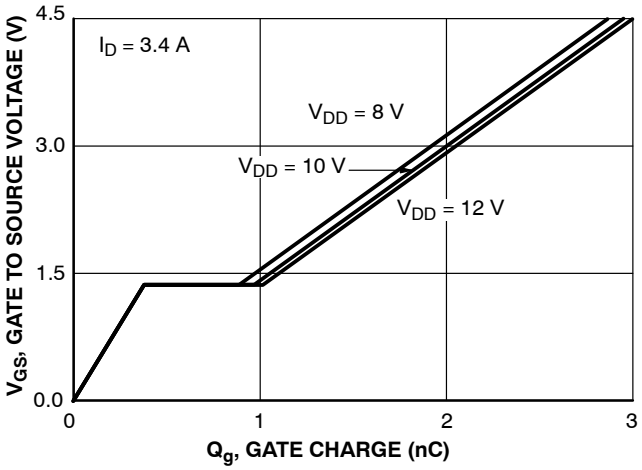


Figure 7. Gate Charge Characteristics

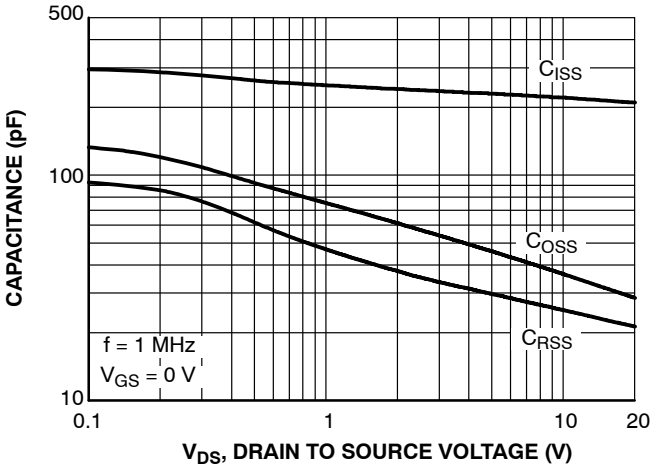


Figure 8. Capacitance vs Drain to Source Voltage

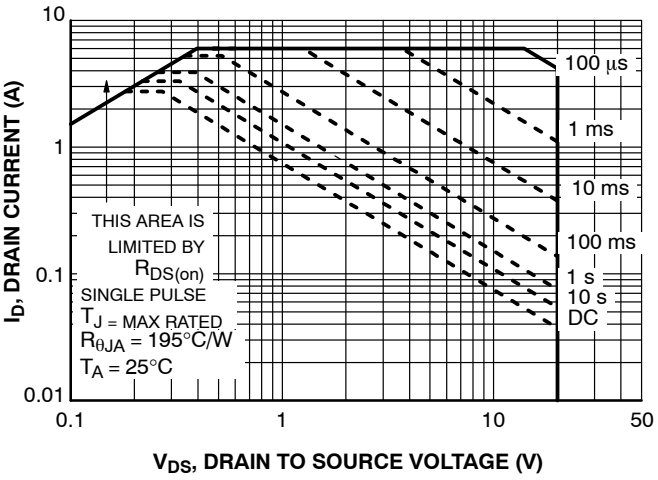


Figure 9. Forward Bias Safe Operating Area

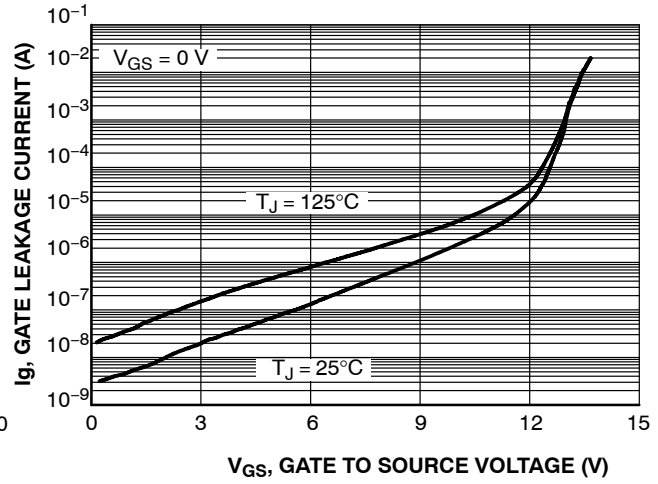


Figure 10. Gate Leakage Current vs Gate to Source Voltage

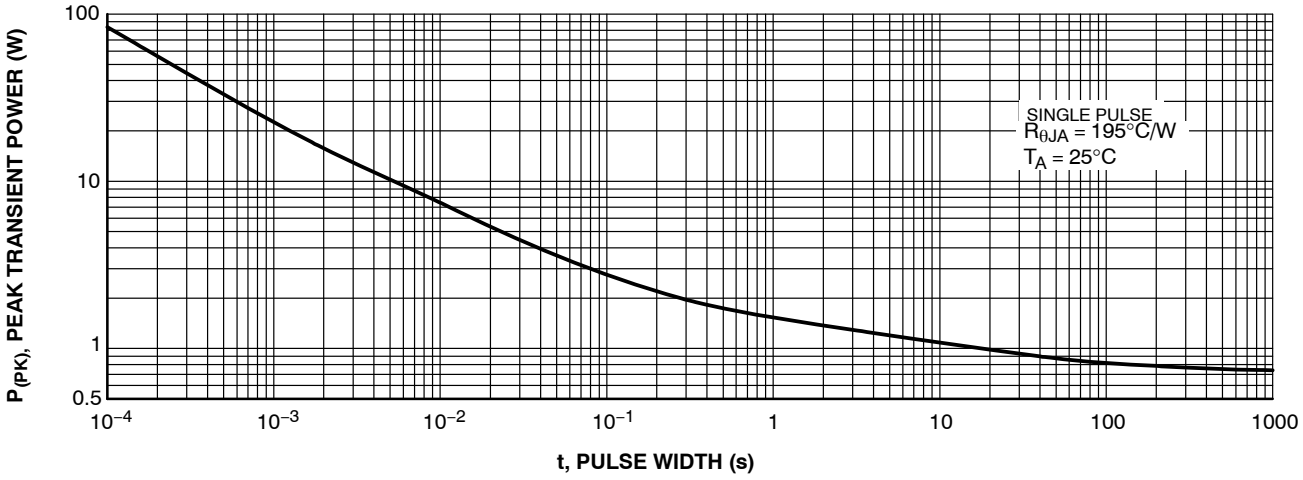


Figure 11. Single Pulse Maximum Power Dissipation

TYPICAL CHARACTERISTICS T_C = 25°C unless otherwise noted (CONTINUED)

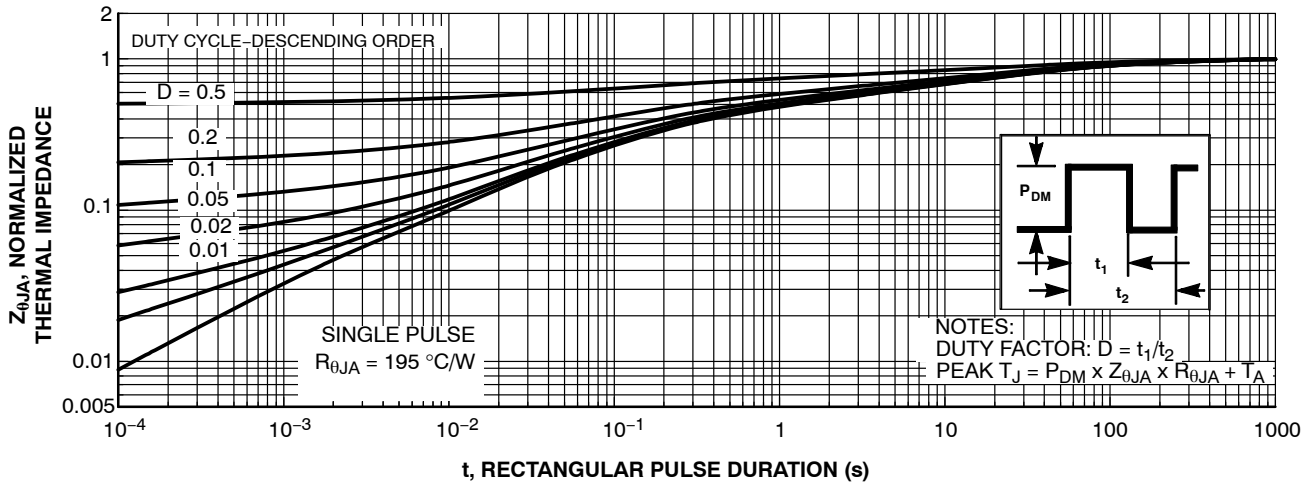
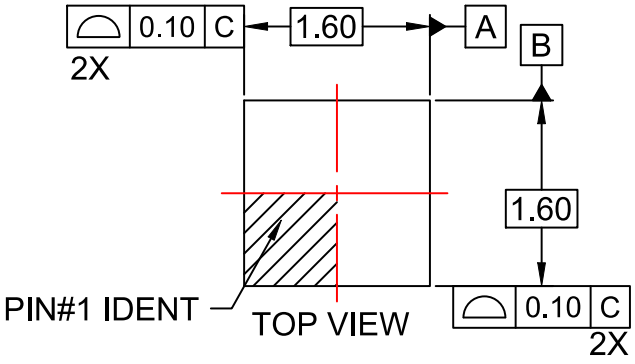
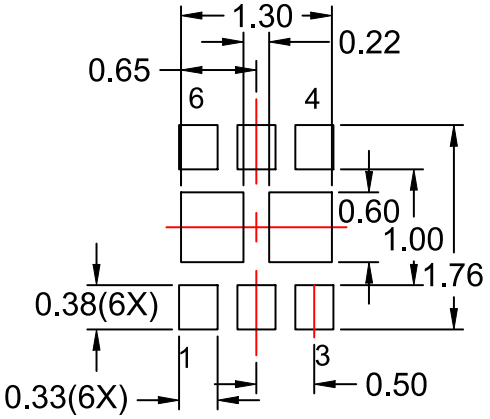


Figure 12. Junction−to−Ambient Transient Thermal Response Curve

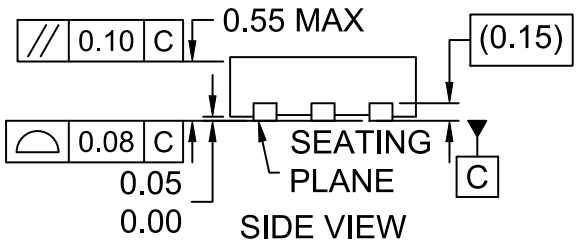
UDFN6 1.6x1.6, 0.5P
CASE 517DW
ISSUE O

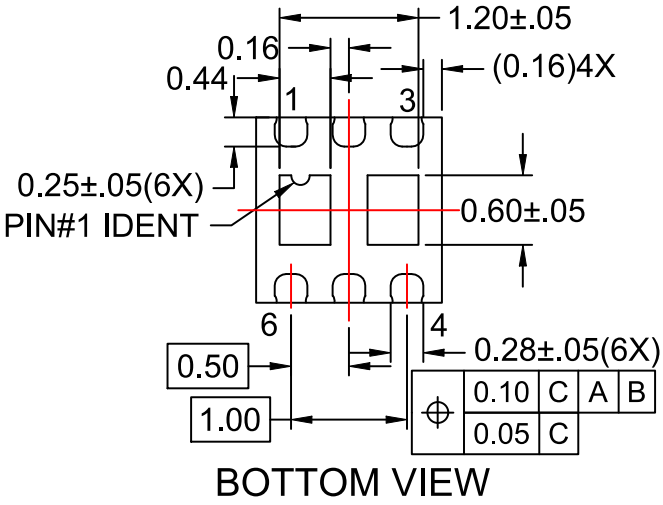
DATE 31 OCT 2016





RECOMMENDED
LAND PATTERN





NOTES:

A. PACKAGE DOES NOT CONFORM TO ANY JEDEC STANDARD.
B. DIMENSIONS ARE IN MILLIMETERS.
C. DIMENSIONS AND TOLERANCES PER ASME Y14.5M, 2009.
D. LAND PATTERN RECOMMENDATION IS EXISTING INDUSTRY LAND PATTERN.

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